

Hybrid Test – Flying Probe & Scanworks:

1. Low NRE with excellent test coverage.
2. Per unit test cost reduction.
3. Scanworks testing of boundary scan devices and interconnect logic.
4. Flying Probe testing of analog components.
5. NZT testing of all nets using Flying Probe.
6. ElectroScan test coverage determined by Scanworks test coverage.
7. Full flying probe program available if additional debug is required.
8. Scanworks test available for standalone testing.

ICT (Agilent 3070 Series 3):

1. Access is limited by mechanical design of PCB.
2. High throughput lowers per unit test cost.
3. High NRE in fixture and program.
4. Less failure debug times due to component based test.
5. ECO can be expensive if fixture modifications are required.
6. Scanworks can be integrated at ICT.

Flying Probe (SPEA 4040XL):

1. Access to all nets.
2. Reduced NRE for both program and fixture.
3. Full analog component coverage.
4. Limited power on test capability.
5. NZT (Nodal Impedance Test) capability (Optional).
6. ElectroScan (vectorless test) capability (Optional).
7. Visual inspection for presence (Optional).
8. Highest per unit test cost.
9. Excellent for debug of “bone pile” boards.

Scanworks:

1. Active test of Boundary Scan devices and interconnect logic.
2. Net based test.
3. Can be standalone test or integrated with ICT.
4. Presence test of analog components in boundary chain.
5. Can be used as bench top or field test system.